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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

NEW Atty. Dkt. No.: 2775-001

Elwin M. BEATY et al.

OLD Atty. Dkt. No.: 2371

Appln. No.: 09/351,892

Filed: July 13, 1999

Group Art Unit: 2621

Conf. No.: 1396

Examiner: S. Chawan

Title: METHOD AND APPARATUS FOR THREE  
DIMENSIONAL INSPECTION OF  
ELECTRONIC COMPONENTS

\* \* \* \* \* \* \* \* \* \* \* \* \* \* \* \* \*  
AMENDMENT UNDER 37 C.F.R. § 1.111  
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RECEIVED

OCT 16 2002

Technology Center 2600

Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

In reply to the Office Action mailed April 11, 2002, please  
amend the above-identified patent application as follows:

IN THE CLAIMS:

Amend claim 30 to read as follows:

*Sub B6*  
30. (Once Amended) A method for three dimensional  
inspection of a lead on a part, the method comprising the steps  
of:

using a camera to receive an image of the lead;  
transmitting the image of the lead to a frame grabber;  
providing fixed optical elements to obtain a side  
perspective view of the lead;